



Current status of Hamamatsu Si detectors for ILC Experiment

HAMAMATSU PHOTONICS K.K.

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May.30.2018

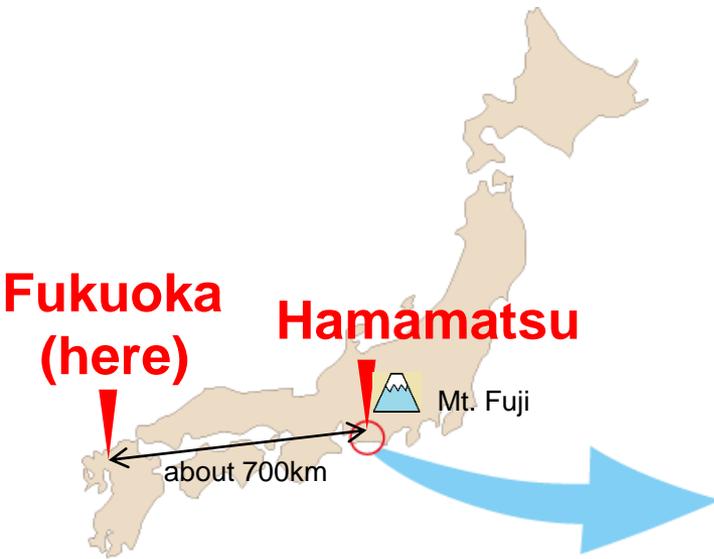
HAMAMATSU PHOTONICS K.K.
Solid State Division

Outline

- 1. HPK's Si detector is used various HEP experiments**
- 2. Si-PAD for ILD E-cal**
- 3. Development of large area PAD detector**
- 4. MPPC® (Multi Pixel Photon Counter)
for HEP application**

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- 1. HPK's Si detector is used various HEP experiments**
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 3. Development of large area PAD detector
 4. MPPC® (Multi Pixel Photon Counter)
for HEP application

Where is Hamamatsu?



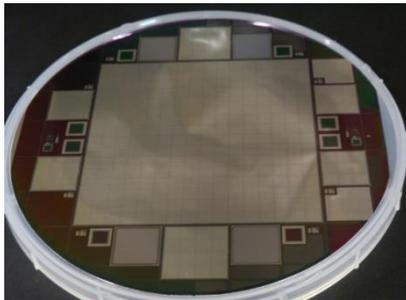
ETD main factory



Hamamatsu Si detectors for HEP

Particle detection

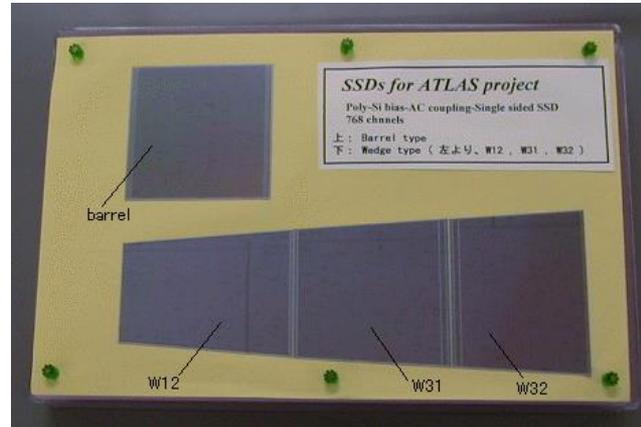
- Silicon Strip Detector(SSD)
- Silicon Pixel Detector
- Silicon PAD Detector**



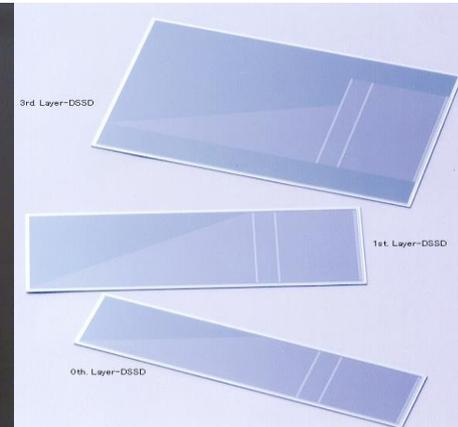
PAD
(for calorimeter)

Photo detection

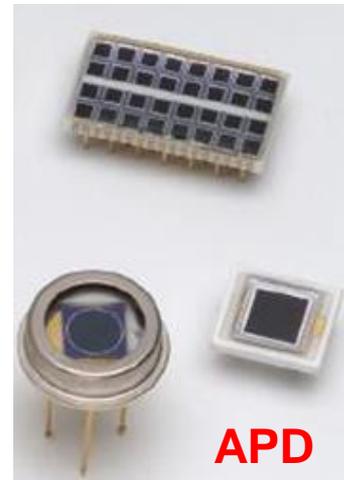
- Silicon Photo Diode(PD)
- Silicon Avalanche Diode(APD)
- Multi Pixel Photon Counter(MPPC®)**



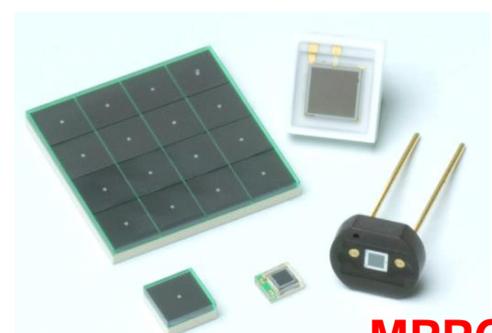
SSSD(for tracker)
(e.g. ATLAS,CMS)



DSSD(for tracker)
(e.g. BELLE)



APD



MPPC

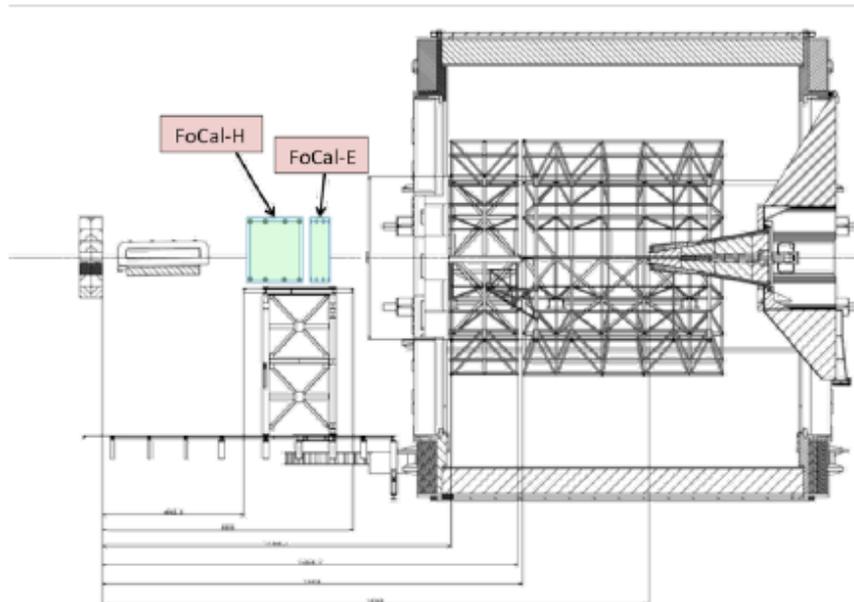
Review of Si-strips and Si-PADs produced by Hamamatsu

PROJECT	DETECTOR TYPE	size	QTY.	period
ATLAS	AC-SSSD 6type , poly-Si	1chip/4inch	16000	2001~2003
GLAST	AC-SSSD , poly-Si	1chip/6inch	11500	2001~2003
CMS	AC-SSSD 14type , poly-Si	1chip/6inch	24000	2003~2006
LHC-b	AC-SSSD , poly-Si	1chip/6inch	560	2005~2006
ALICE	AC-SSSD 2type , poly-Si	1chip/6inch	106	2005~2006
Phenix	Strippixel , DML	3chip/6inch	600	2007
PP2PP	AC-SSSD 2type , poly-Si	1chip/6inch	120	2003~2007
FVTX	AC-SSSD 2type , poly-Si	3chip/6inch	450	2009~2010
ASTRO-H	DC-SSSD , DC-PAD , DML , DML	3chip/6inch	260	2007~2011
STAR-HFT	AC-SSSD	2chip/6inch	216	2012
HALL-B	AC-SSSD	1chip/6inch	434	2012
BELLE-II	AC-SSSD	1chip/6inch	265	2011~2014
DAMPE	AC-SSSD , poly-Si	1chip/6inch	768	2014
ALICE-FoCal(mini)	DC-PAD	1chip/6inch	61	2017

-Topics-
2018.4.26
the First collision!

Recently, HPK has shipped(pick up shortly today).

Forward Calorimeter (FoCal) in ALICE



- Electromagnetic calorimeter for γ and π^0 measurements, with Hadron Calorimeter.

- At $z \approx 8\text{m}$ (outside magnet)
 $3.3 < \eta < 5.3$

- **Proposed schedule:**
 - mini-FoCal: 2018- (after LS2)
 - full FoCal: 2023- (after LS3)

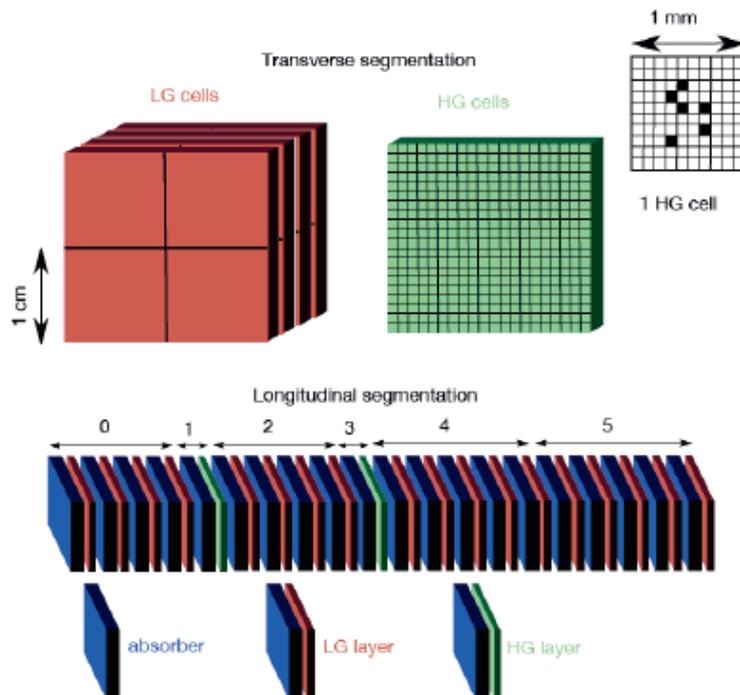
Main challenge: **separate γ/π^0** at high energy

- Need small Molière radius, high-granularity read-out
- Si-W calorimeter, granularity $\approx 1\text{mm}^2$

*This slide is provision by Dr.Tatsuya.Cyujo/University of Tsukuba



FoCal-E Strawman Design



- Si/W sandwich calorimeter layer structure:
 - W absorbers (thickness $1X_0$) + Si sensors
- Longitudinal segmentation:
 - 4 segments low granularity (LGL)
 - 2 segments high granularity (HGL)

• LGL segments (PAD)

- 4 (or 5) layers of Si/W
- Si-PAD with analog readout
- cell size $1 \times 1 \text{ cm}^2$
- $8 \times 8 = 64$ PADs per layer
- signal are longitudinally summed

• HGL segments (MAPS)

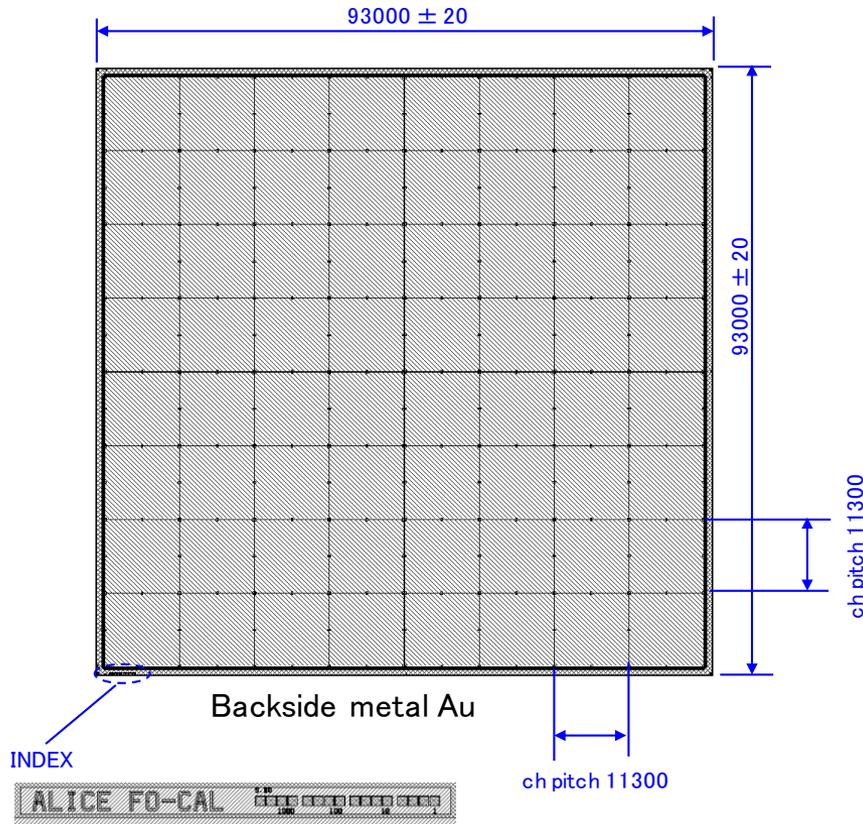
- single layer with W.
- CMOS-pixel (MAPS*).
- pixel size $\approx 25 \times 25 \mu\text{m}^2$
- digitally summed in 1 mm^2 cells

*MAPS = Monolithic Active Pixel Sensor

*This slide is provision by Dr.Tatsuya.Cyujo/University of Tsukuba

Specification of Si-PAD for Alice-FoCal

Chip overall



(Serial No. is scratched by BCD)

HAMAMATSU

Si Photo Diode
S10938-6475

General ratings

Parameter	Rating	Unit
Detector type:	PIN-PD array	
Orientation of crystal:	<100>	
thickness:	320 ± 15	μm
Dead thickness at backside	20	μm
Chip size	93 x 93 ± 0.02	mm
Number of ch	64 (8 x 8)	ch
PAD pitch(X):	11300	μm
PAD pitch(Y):	11300	μm
Single ch P+ size:	11250 x 11250	μm
Single ch Al size:	11280 x 11280	μm
Readout PAD size:	200 x 200	μm

-Rough result-

Id(typ) <1nA/ch @200V
Ct(typ) 47pF/ch@200V
Vfd 45V

-
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 3. Development of large area PAD detector
 4. MPPC® (Multi Pixel Photon Counter)
for HEP application

Specification of Si-PAD for ILD E-cal (thicker ver./Shipped 2018.3)

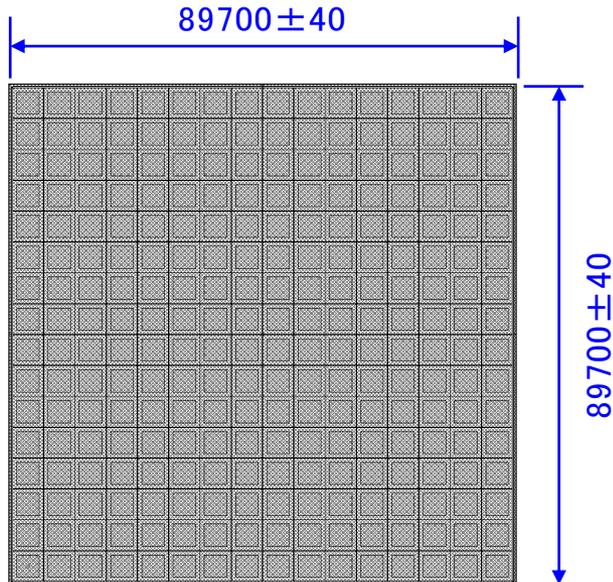
■ General Ratings

Current ver.

Parameter	Rating	Unit
Device type	P+ PIXEL on N substrate	
Chip size	89700 ± 40 x 89700 ± 40	μ m
Active area	88480 x 88480	μ m
Chip thickness	320 ± 15 or 500 ± 15	μ m
Number of PIXELs	256(16 x 16)	ch
PIXEL pitch	5530 x 5530	μ m
PIXEL GAP	10	μ m

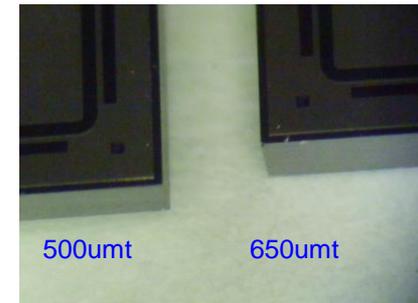
Thicker ver.

Parameter	Rating	Unit
Device type	P+ PIXEL on N substrate	
Chip size	89700 ± 40 x 89700 ± 40	μ m
Active area	88480 x 88480	μ m
Chip thickness	650 ± 15	μ m
Number of PIXELs	256(16 x 16)	ch
PIXEL pitch	5530 x 5530	μ m
PIXEL GAP	10	μ m



active area
88480 x 88480

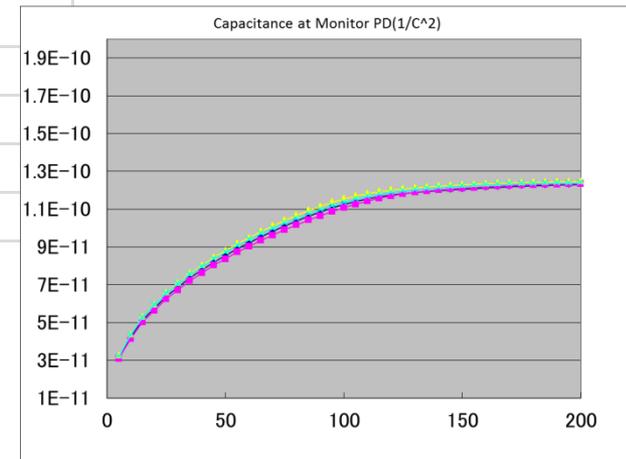
Back Side:
Common Cathode(All metalization/pure Al)



Inspection result of Si-PAD for ILD E-cal (thicker ver./Shipped 2018.3)

chipNo.	1	Leakage current[nA]										Id TOTAL					238	[nA]
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15		
1	4.0	1.9	1.7	1.7	1.5	1.6	1.4	1.5	1.5	1.4	1.6	1.5	1.6	1.6	2.1	3.9		
2	2.2	0.6	0.6	0.5	0.5	0.5	0.5	0.5	0.7	0.6	0.7	0.5	0.9	0.8	0.6	1.9		
3	1.7	0.6	0.9	1.6	0.5	0.5	0.5	0.5	0.6	0.6	0.5	0.8	0.5	1.2	0.6	1.7		
4	1.9	0.6	0.6	0.8	0.5	0.5	0.5	0.5	0.9	0.6	0.5	0.5	0.5	0.6	0.7	1.6		
5	1.5	0.6	0.6	0.5	0.6	0.5	0.5	0.6	0.8	0.6	0.6	0.6	0.5	0.9	0.7	1.5		
6	1.6	0.5	1.6	1.0	0.6	0.5	0.8	0.7	0.6	0.6	0.8	0.7	0.6	0.6	0.6	1.6		
7	1.6	1.3	0.5	0.9	0.5	0.5	0.8	0.9	0.6	0.7	0.7	0.7	0.6	0.7	0.6	1.8		
8	1.9	0.5	0.9	0.6	0.5	0.5	0.7	0.6	0.8	0.9	0.8	0.7	0.6	0.6	0.6	1.9		
9	1.6	0.6	0.5	0.5	0.6	0.5	0.6	0.6	0.7	0.6	0.6	0.9	0.7	0.8	0.7	1.3	1.8	
10	1.7	0.5	0.7	0.5	0.8	0.6	0.7	0.5	0.6	0.7	0.6	0.6	0.6	0.6	0.6	2.1		
11	1.7	0.5	0.5	0.6	0.5	0.5	0.5	0.5	0.6	0.5	0.5	0.5	0.7	0.6	0.8	1.7		
12	1.5	0.6	0.8	0.5	0.6	0.5	0.5	0.5	0.5	0.6	0.8	0.8	0.6	0.7	0.7	1.7		
13	2.0	0.8	0.5	0.5	0.5	0.5	0.5	0.5	0.5	0.6	0.8	0.5	1.0	0.6	0.7	1.8		
14	1.9	0.6	0.7	0.9	0.7	0.5	0.5	0.5	0.5	0.5	0.5	0.6	0.6	0.9	0.7	1.8		
15	2.0	0.7	0.6	0.6	1.2	0.5	0.5	0.8	0.7	0.5	0.8	0.5	0.6	0.6	0.7	2.3		
16	3.7	1.9	1.7	1.6	1.6	2.2	1.6	1.5	1.5	1.7	1.6	1.6	1.7	2.1	1.9	3.7		

12	13	14	15	16
1.5	1.6	1.6	2.1	3.9
0.5	0.9	0.8	0.6	1.9
0.8	0.5	1.2	0.6	1.7
0.5	0.5	0.6	0.7	1.6
0.6	0.5	0.9	0.7	1.5

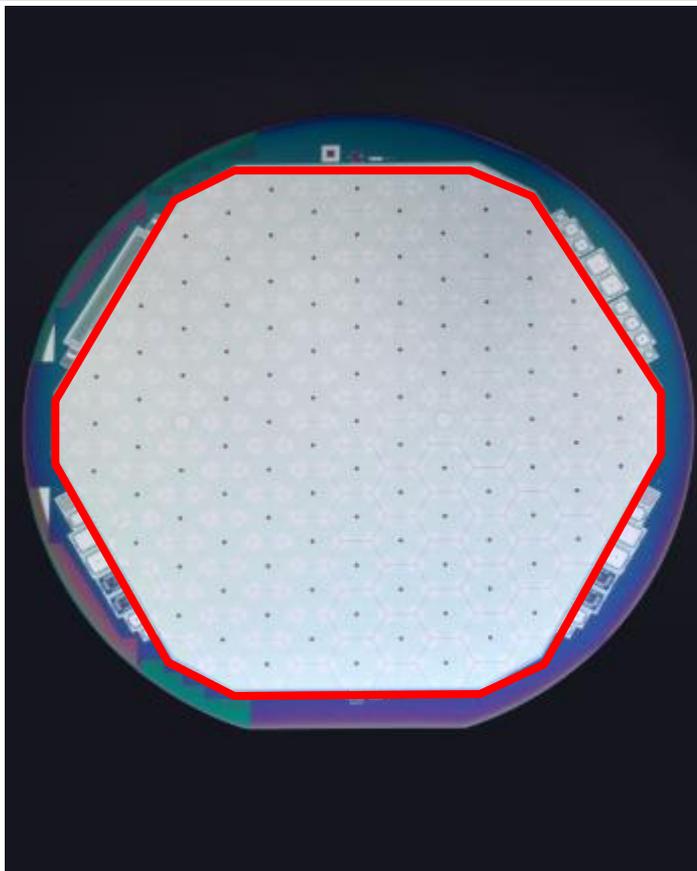


- Very low leakage current typ:0.5nA/ch @200V25°C (at inner ch, typically a few nA at outer ch)
- No NGch
- Vfd:90V

Now in checking(by customer side) and assembling at Kyushu university.

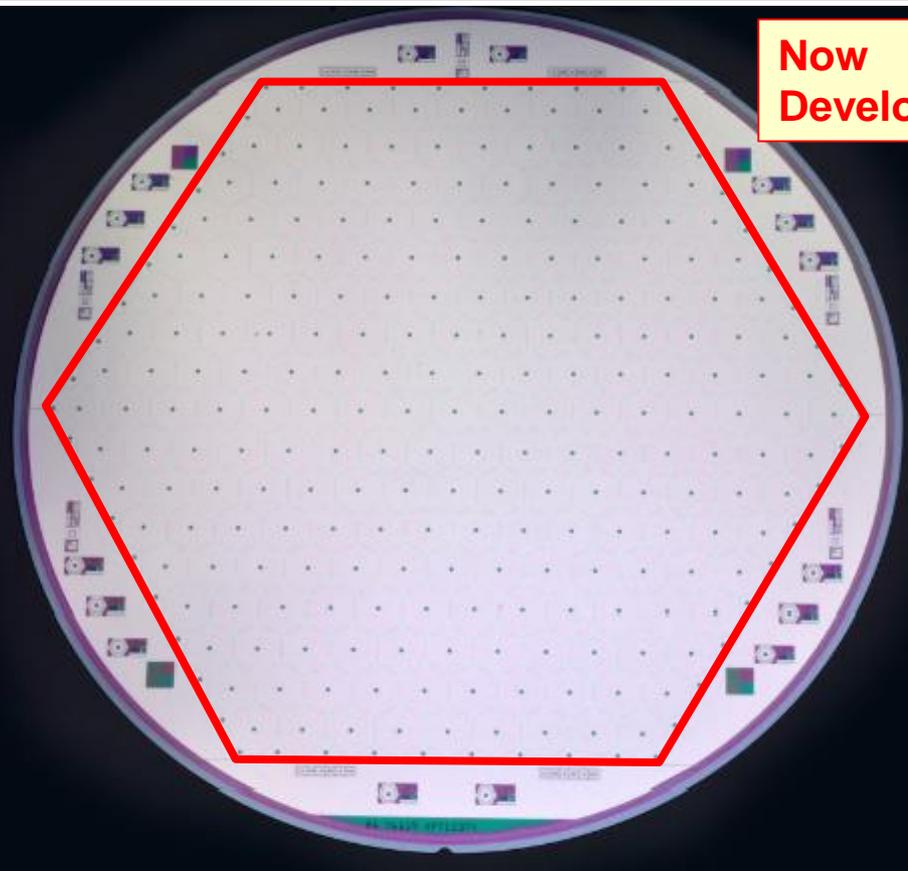
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Development of 8inch-PAD detector



6inch-PAD detector

- 12 Polygon shape chip
- 109 x Hexagonal PADs + α



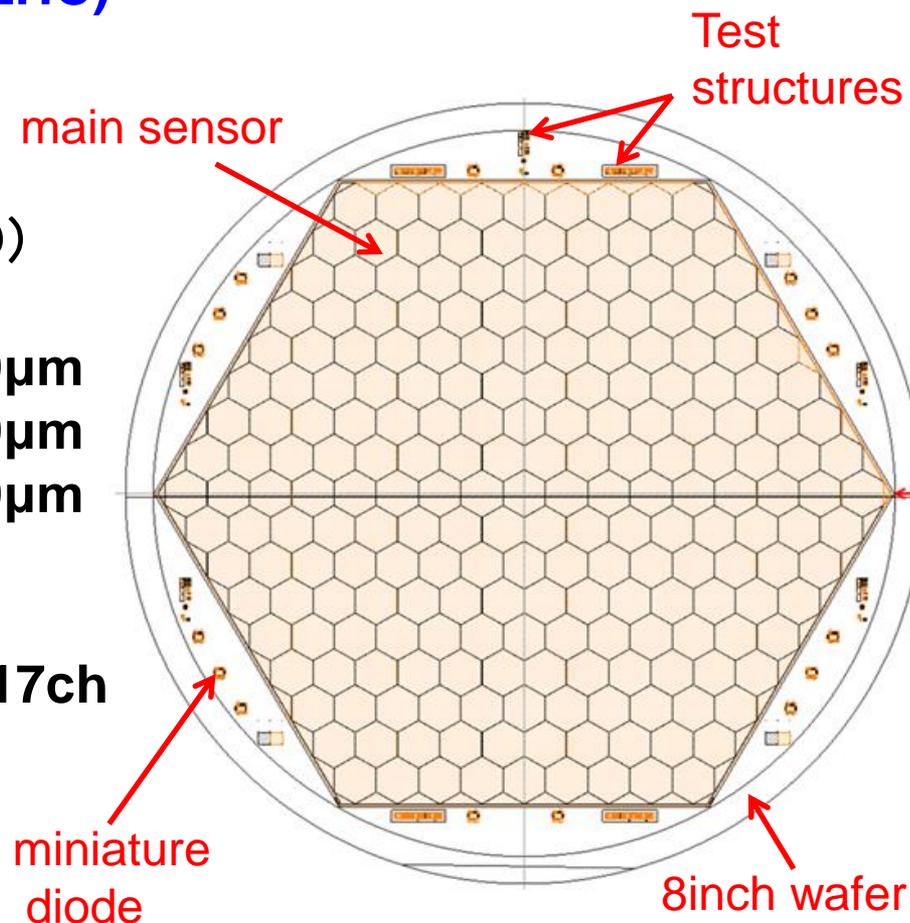
8inch-PAD detector

- Hexagonal shape chip
- 217 x Hexagonal PADs + α

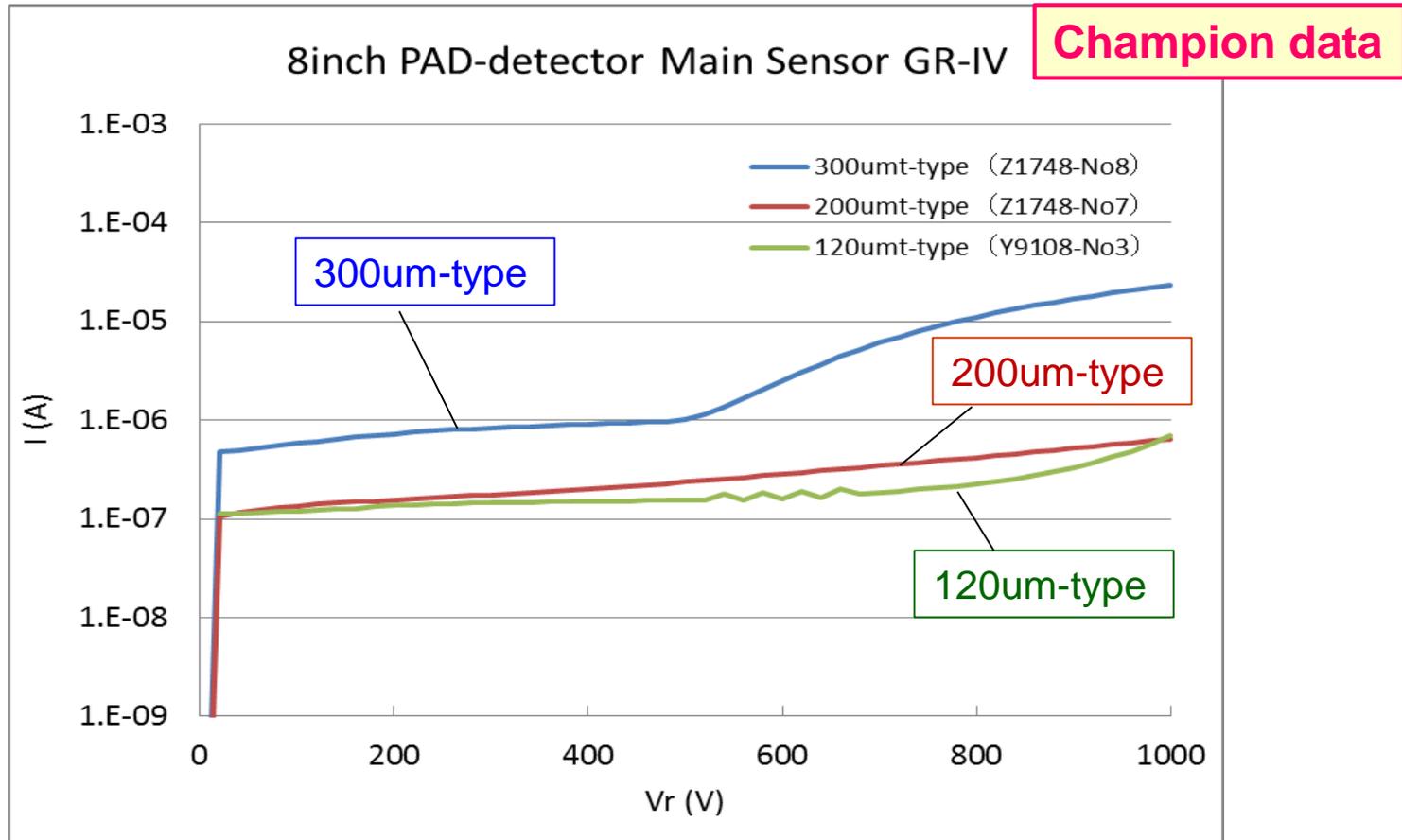
Development of 8inch-PAD detector

■ Our 1st Proto-type (target for CMS-HGCAL HL-LHC)

- Size : 8 inch
- Type : N+ in p
(P-substrate and N-PAD)
- Thickness : 3types
 - Active 300 μ m、Physical 300 μ m
 - Active 200 μ m、Physical 200 μ m
 - Active 120 μ m、Physical 300 μ m
- Size of PAD : ~ 1cm²
- Number of Hexagonal PAD : 217ch



Guard-Ring I-V of Main Sensor

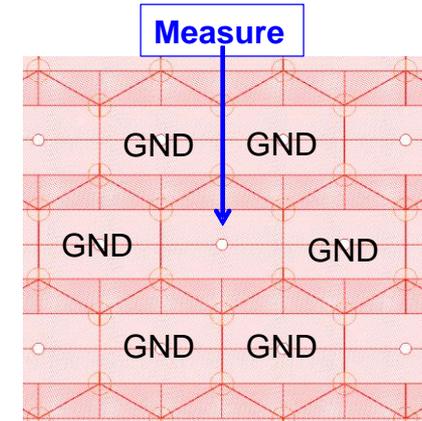


Enough low dark current and high voltage tolerance

Result-2

Channel I-V of Main Sensor

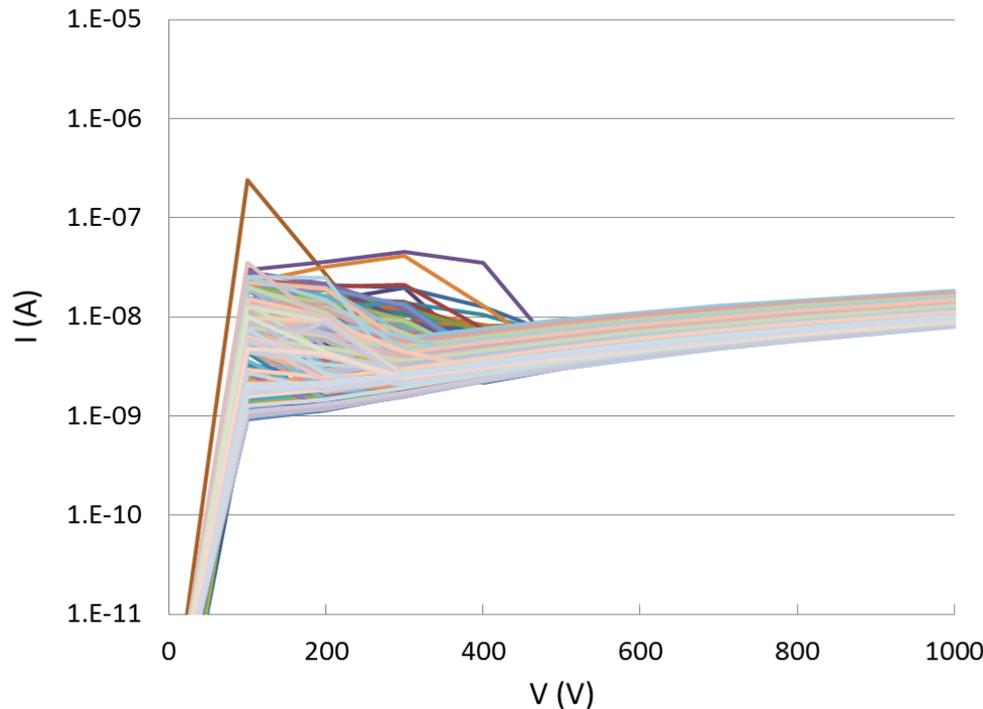
■ We measured IV curve of every channels with surrounded channels GND.



Champion data

200 μ m type

Channel-IV 200um-type (Z1748-WNo7)



As well as GR-IV results,
We got good results.

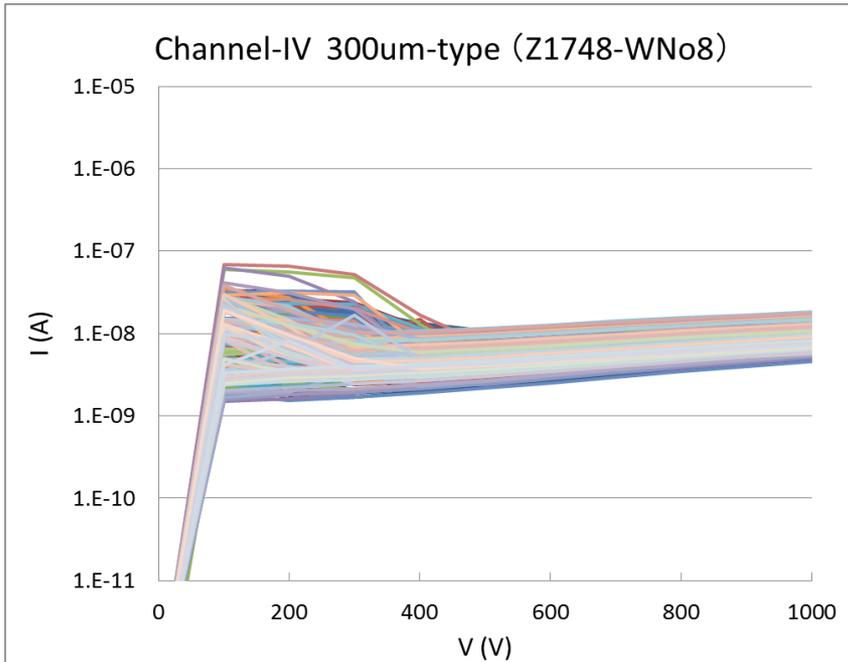
Result-2

Channel I-V of Main Sensor

- We measured IV curve of every channels with surrounded channels GND.

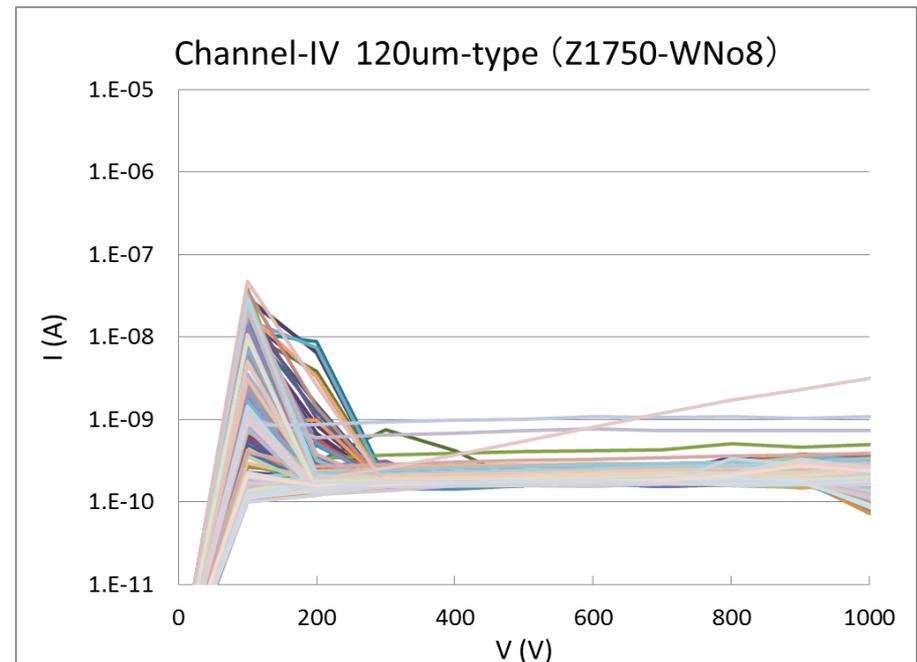
Champion data

300 μ m type



Similar result as 200 μ m type

120 μ m type

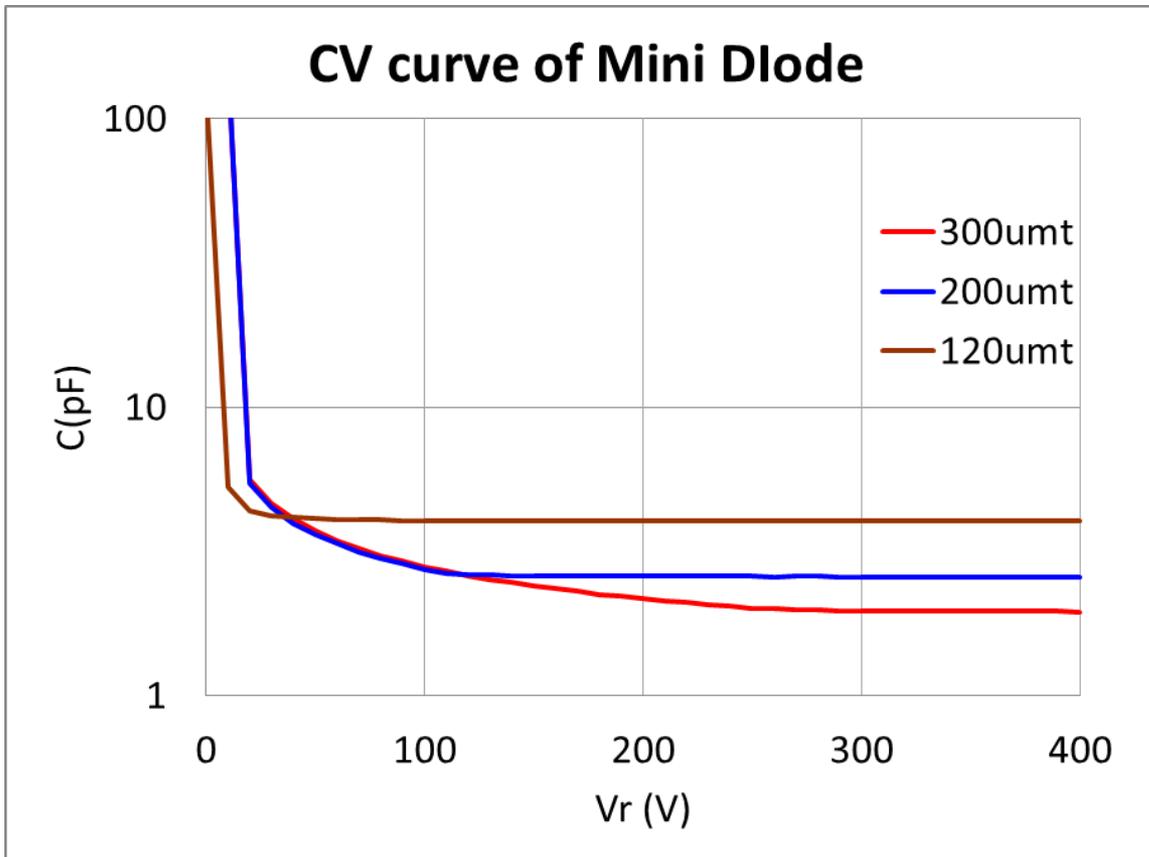
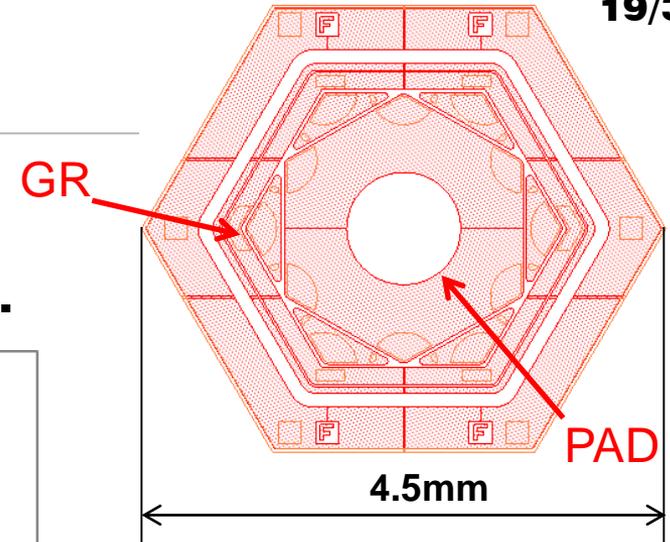


Lower leakage current than Other types

Result-3

C-V curve of Mini Diode

■ We measured CV curve of Mini Diode and estimated the full depletion voltage.



Full depletion voltage

300 μ m type : ~280V

200 μ m type : ~130V

120 μ m type : ~ 30V

Future prospect of 8inch wafer production

○DC-type : PAD-detector, PIXEL

- Development stage ~2019
- will be available 2020~

○AC-type : AC coupled SSD

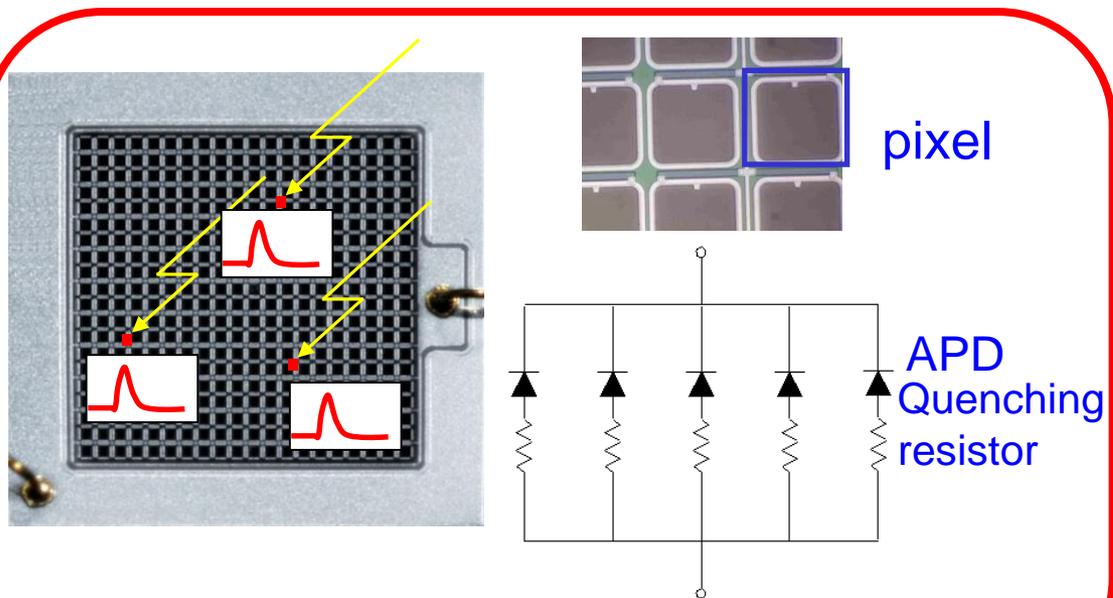
- Development stage 2020~2022
- will be available 2023~

-
1. HPK's Si detector is used various HEP experiments
 2. Si-PAD for ILD E-cal
 3. Development of large area PAD detector
 4. **MPPC® (Multi Pixel Photon Counter)
for HEP application**

MPPC[®] Technology Overview

➤ What is an MPPC[®]?

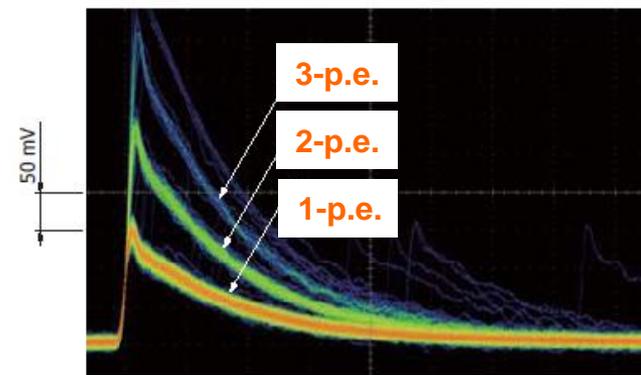
- **M**ulti-**P**ixel **P**hoton **C**ounter
a new type of photon-counting device
made up of multiple APD pixels
operated in Geiger mode (=SiPM)



Output is summation of all pixel output

➤ Features

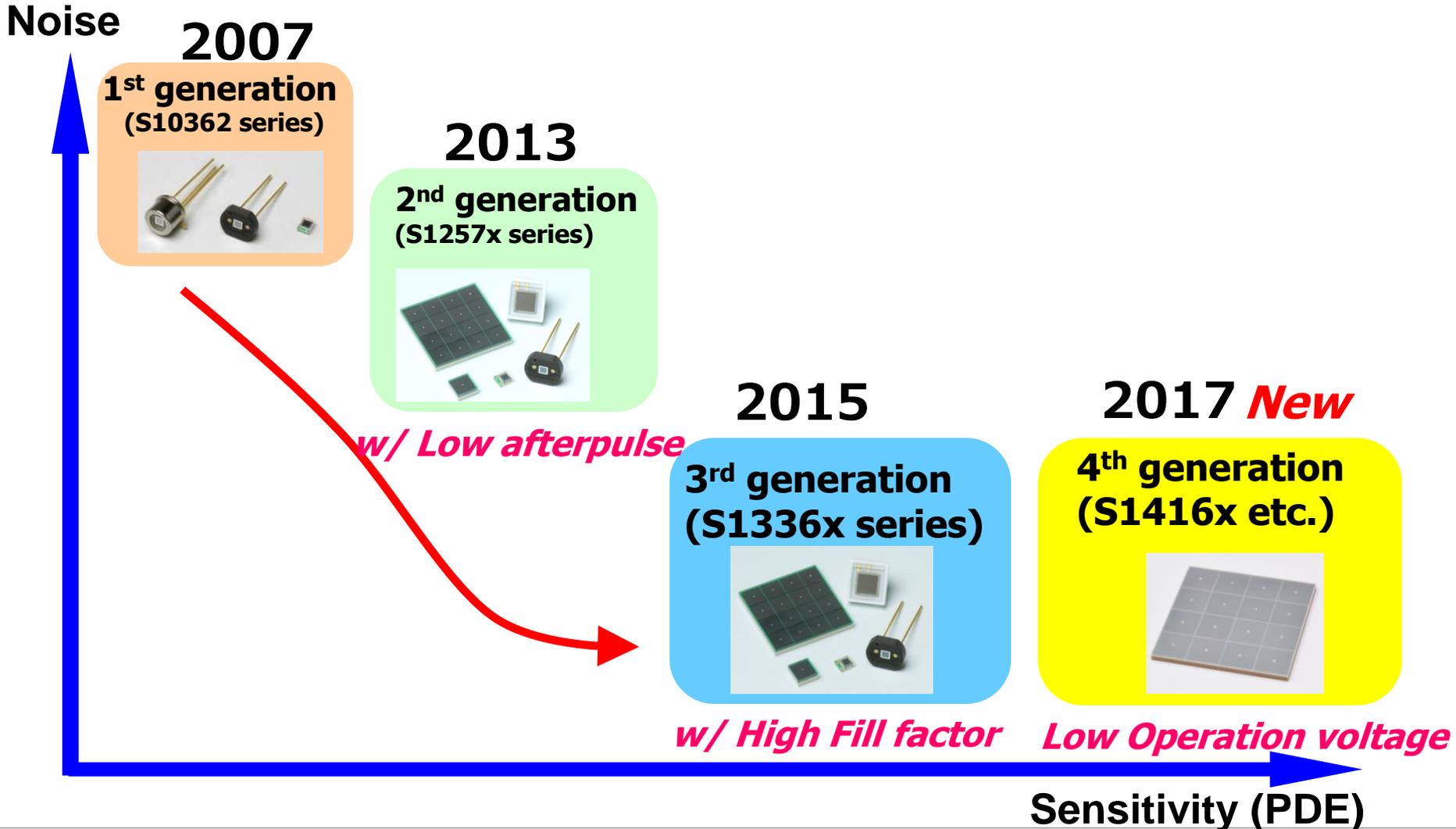
- Small size / light weight
- Room temperature operation
- Low bias operation : **40~70V**
- High gain: 10^5 to 10^6
- Excellent timing resolution
- Insensitive to magnetic fields
- Simple readout circuit operation



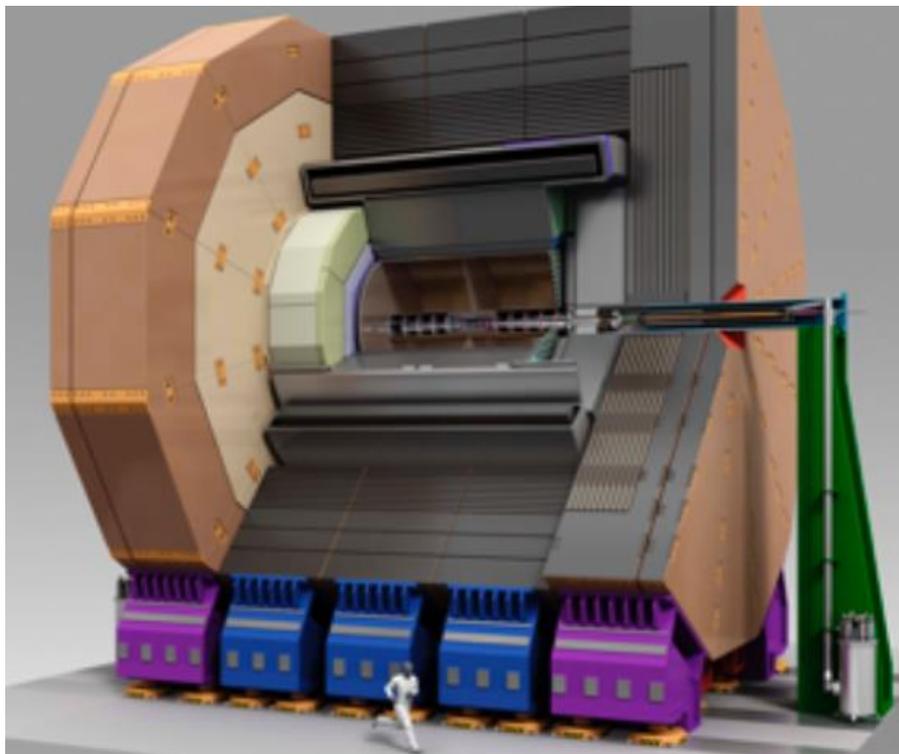
$$Q_{out} = N_{fired} \times C_{pixel} \times (V_{op} - V_{BR})$$

$$N_{fired} = PDE \times N_{photon}$$

History of MPPC[®]s



MPPC in Accelerator



- ❑ Accelerator is consisted by some detector which is designed for detecting timing, position and energy.

- ❑ MPPC has been used in any type of detectors.
 - Tracker
 - Timing detector
 - Calorimeter
 - Muon detector

- ❑ Most especially, calorimeter is suitable detector for MPPC.

MPPC in calorimeter

- ◆ Determine particle energy by scintillator ($\lambda_p = 350\text{-}550\text{nm}$)
 - A) Coupled directly (bar or fiber; LYSO, CsI, plastic, etc.)
 - B) Coupled with wavelength shifter(WLS) fiber

Both are match to MPPC's sensitivity peak

◆ MPPC in calorimeters

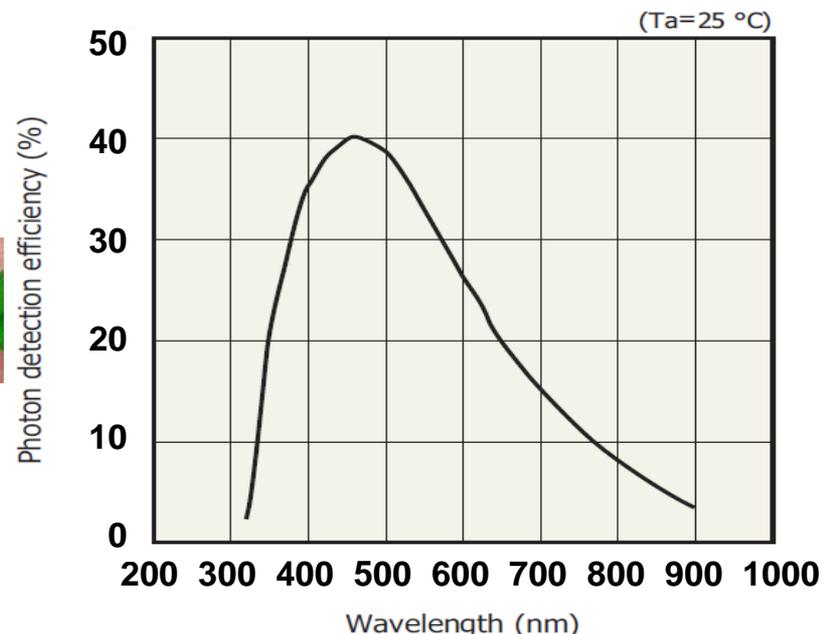
CMS/LHC, mu2e, NICA etc.
(& ILC !?)



MPPC for CMS/LHC

◆ Request

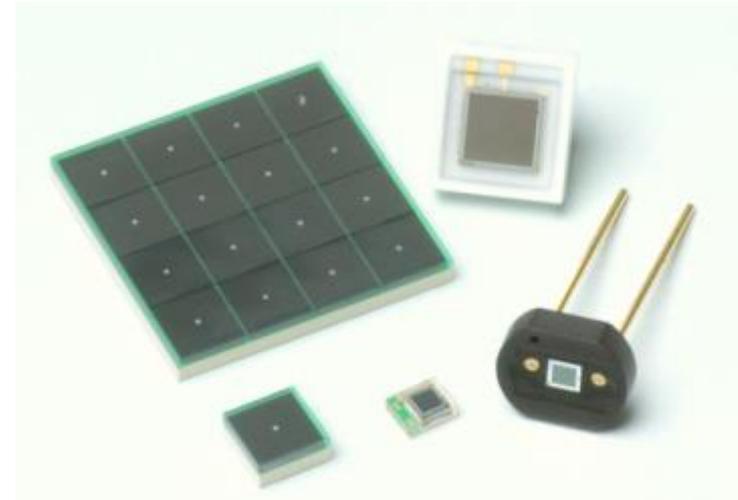
- **Dynamic range**
- **High sensitivity**
- **Radiation hardness**



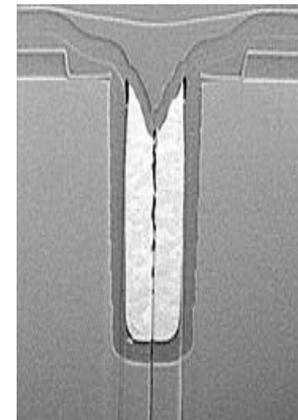
MPPC for general propose

S13360 series

- Low noise (dark count, cross-talk)
- High count rate (fast recharging)
- Excellent timing resolution
- High blue light sensitivity
→ *match to scintillator emission*
- Single & TSV array lineup
 - *Suitable for any application*



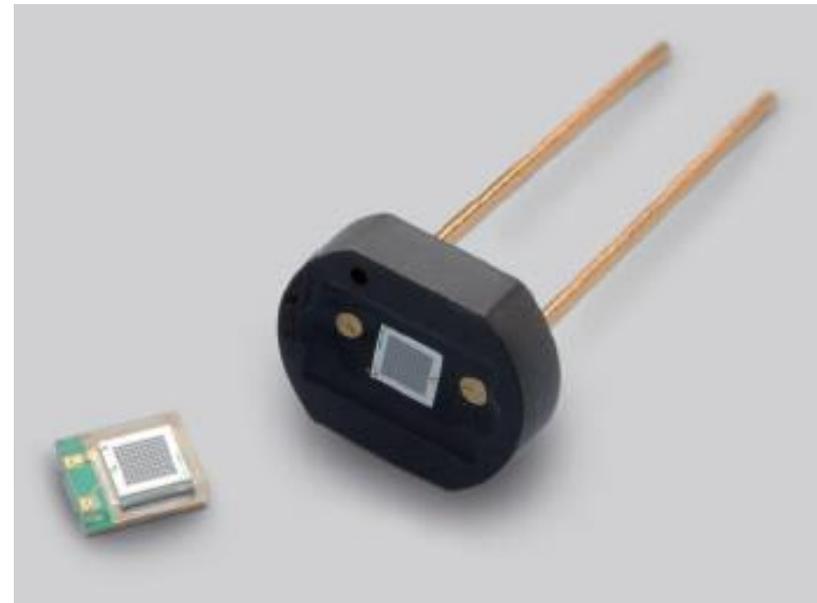
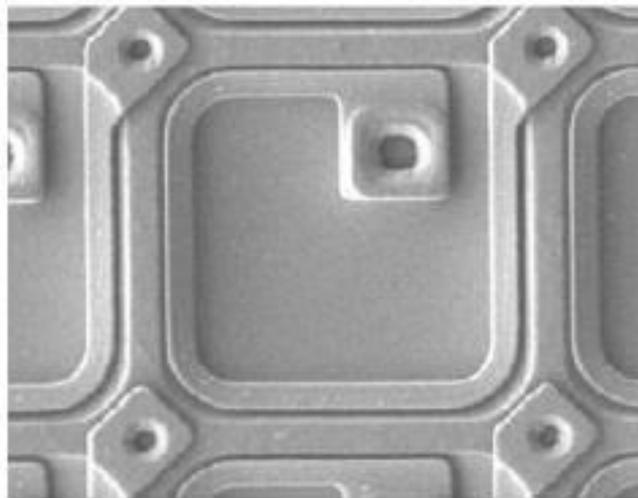
Trench isolation
(between pixel to pixel)



High dynamic range type

S12571/S12572-010, -015C/P

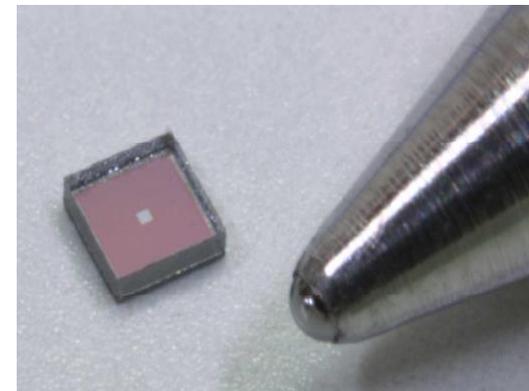
- High-dense pixels (10/15 μ m) & high dynamic range
- High PDE (maximized fill factor)
- S1257x-015 is known as a good radiation hardness device.
 - Suitable for *calorimeter*.



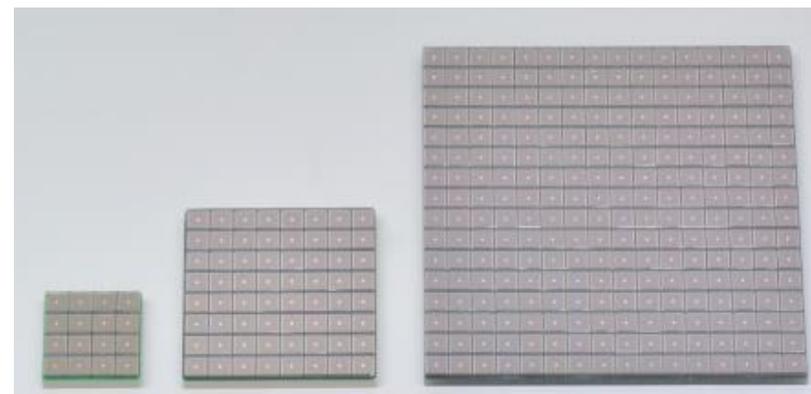
Wafer Level Chip Size Package (WLCSP)

S13190 & S13615 Series

- **1x1mm² TSV with support glass**
- **Small and compact**
Package size: 1.13mm SQ.
(Active area : 1.0mm SQ.)
- **4-side tillable & high density assembly**



- ***S13190: High dynamic range type**
- S13615: Low noise type**



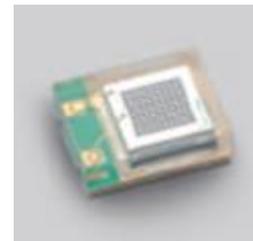
MPPC for ILC

【H-CAL】

S13360-1325PE (low noise type)

S13615-custom

(1mm²-2x2ch.-25ump, 4 ch. parallel connected)



【EM-CAL】

S12571-015P, -010P

(high dynamic range type)



Radiation hardness

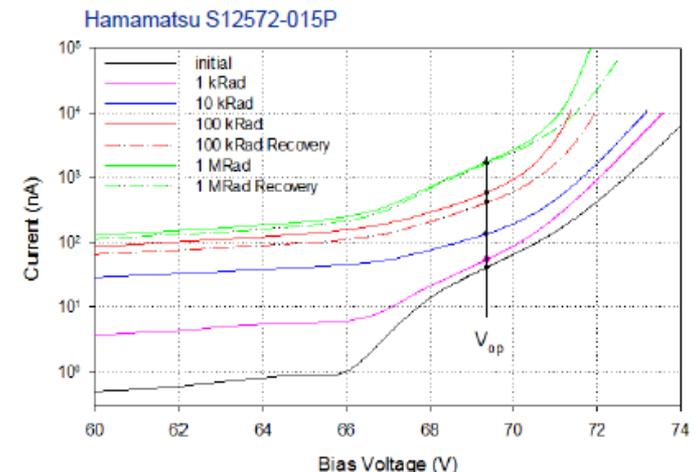
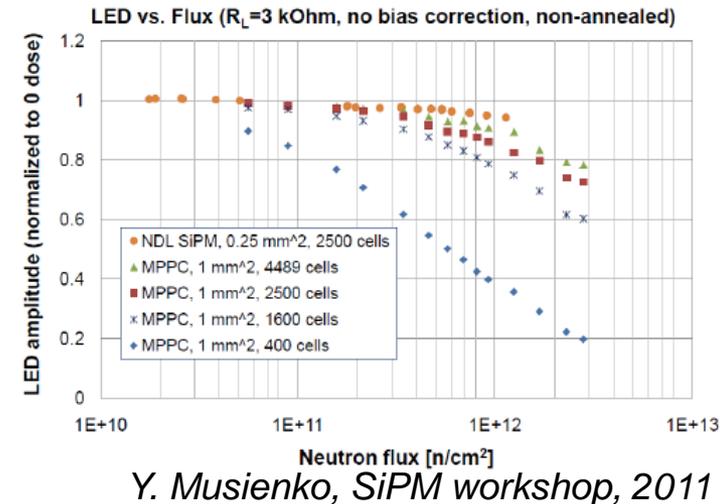
Bulk damage:

- Irradiated **particle** create the defect in MPPC and affect some characteristics (noise, PDE, gain).
- Maximum permissible irradiation:
 $\sim 10^{12}$ (1MeV neq/cm²)

Surface damage:

- Low energy **X-rays** can produce surface damage affecting the passivation layer.
- **Ionizing particles** can produce charging up effects affecting the internal fields inside MPPC.
- Maximum permissible irradiation:
 Depend on the particle and energy.
 (ex. 60Co-1Mrad: $I_d \sim 100$ times)

Smaller pixel sizes show less damage.



C. Woody, CPAD Workshop, 2016

Development for NEXT

Motivation

◆ High dynamic range

→ *Smaller pixel*

◆ Good energy resolution

→ *High PDE & Noise suppression*

◆ Anti-electric noise

→ *High gain*

◆ Radiation Hardness

→ *Lower overvoltage operation(= low noise)*

HDR2(High dynamic range 2) is under development!

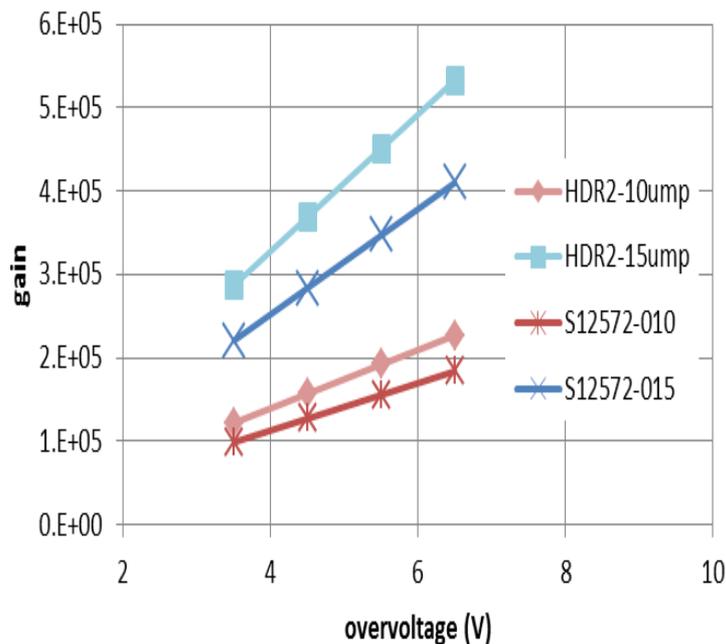
MPPC-HDR2 (Under development)

4th generation MPPC family; High dynamic range type

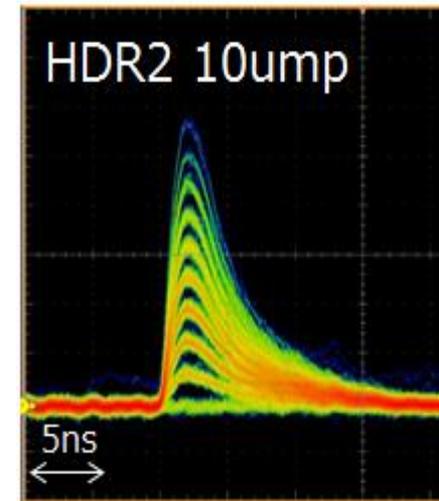
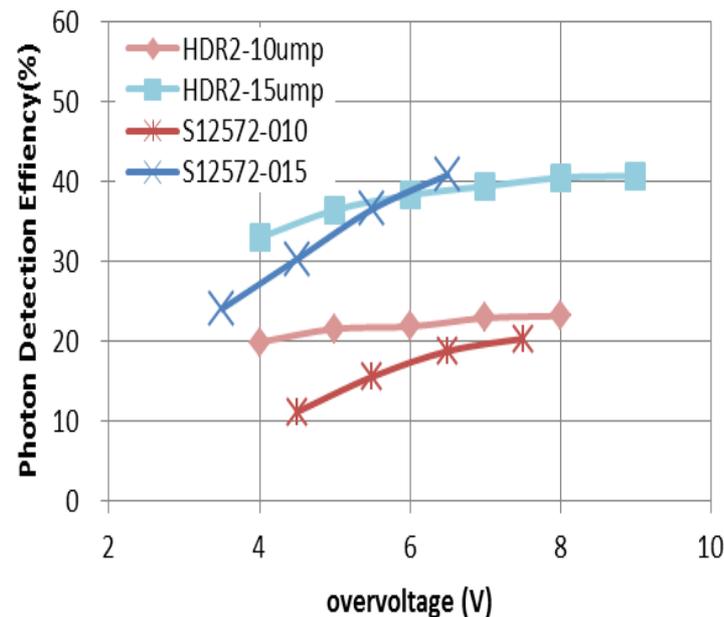
- ◆ Low bias operation: $V_{br} \sim 40V$ (*S1257x: $V_{br} \sim 65V$)
- ◆ High gain & high PDE even low overvoltage

[Preliminary results]

Gain



Photon Detection Efficiency($\lambda=450nm$)



MPPC-HDR2 (Under development)

Noise characteristics

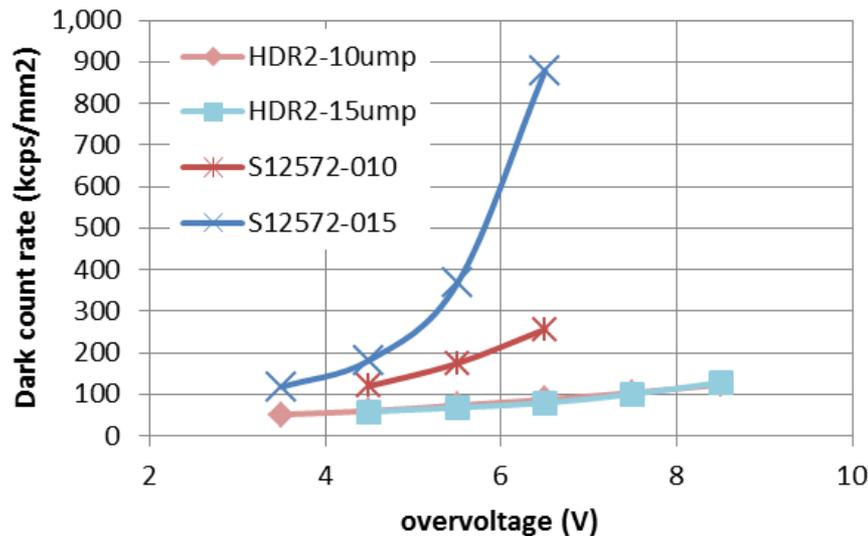
◆ Dark count rate and crosstalk probability is suppressed by trench isolation technology.

➡ S/N ratio and energy resolution will be improved!

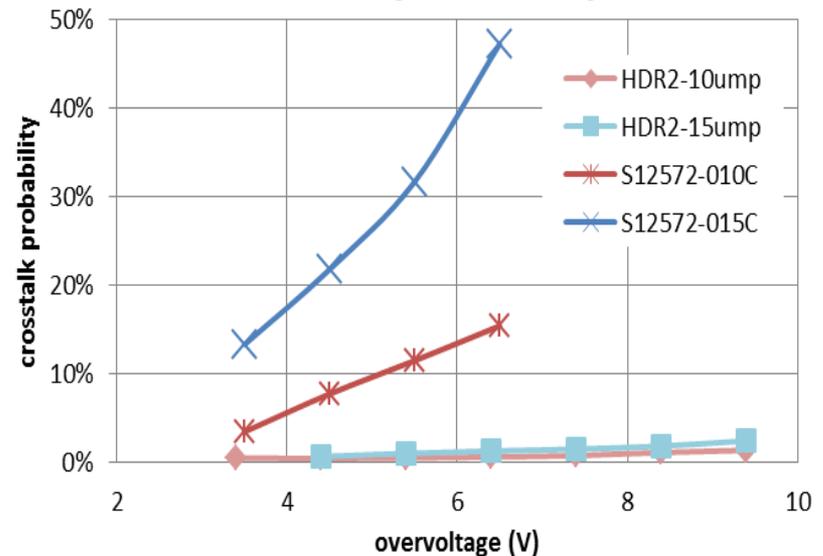
(Now checking reliability and radiation hardness)

[Preliminary results]

Dark count rate



Crosstalk probability



Summary

- 1. The Hamamatsu SSDs and PADs sensors have been used various HEP experiments.**
- 2. Also, We are now developing for ILC.**
- 3. In parallel, We are now developing 8-inch PAD detector, and we have obtained several trial results.**
- 3. We have developed and delivered MPPC[®] s for HEP experiments as well as PADs.**
- 4. New high dynamic range MPPC[®] (MPPC-HDR2) is under development. High PDE, low noise and high dynamic range characteristics will contribute to the calorimeter's improvement.**

Closing

We Hamamatsu are proud that our Si-detectors are used for many physical experiments.
We continually make efforts to provide a better sensor, and contributes to the development of physics.



Photo of Ichino factory with beautiful cherry blossom



Awards received from the LHC experimental groups

Thank you for your attention.

jp.hamamatsu.com